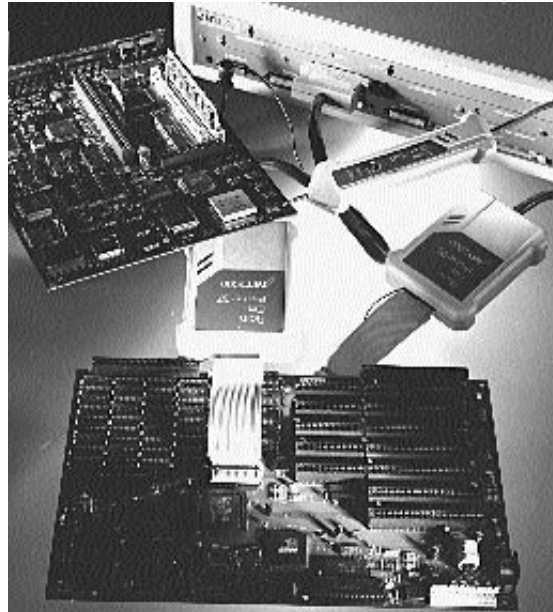


## MT2000 i960® Processor Test and Repair System

- Minimal Set-Up in Windows Environment With Pre-Programmed Diagnostics and Board Configuration/Set-Up
- Powerful "Dead Kernel Mode"
- Programmable in Visual Basic, Visual C, or "Easy Programming Environment"
- Defect Analyzer Linked to Functional Test Results Giving Accurate Fault Statistics
- One Hardware Configuration Supports Complete Range of i960® Processor Types
- Captured Data May Be Graphically Displayed as Waveforms or as Data (Hex or Binary)
- Auto Compare of Captured Data
- Flash ROM Testing
- Integral 100 MHz Signal Capture Probe
- Node Stimulus Mode
- On-Line Help for All Options



International Test Technologies, an IBM Alliance Company, provides board test and repair solutions based on the MT2000 ROM emulator. A single MT2000 hardware configuration is standard for all i960 processor motherboard types.

The MT2000 has pre-programmed diagnostics for board functional test such as board configuration/set-up, MPU kernel test, short RAM test, long RAM test, DRAM refresh test, read/write memory and I/O, dump memory, fill/check memory, read/write special function register, access to SYSCTL, SDMA and UDMA instructions, memory stimulus, logic probing and no boot mode for dead kernel boards.

Custom test programs may be developed in Visual Basic, Visual C, or Easy Programming Environment. Our Customer Support Group, may also be called upon for support or custom test programming projects.

Once the defective circuit is identified using the functional tests, Node Stimulus Mode generates a known good signal

which is used to stimulate the functional area. A logic probe is used to capture, analyze and compare signals in auto-compare mode. It can be operated in two modes, node stimulus mode and no-boot mode. Both modes facilitate the capturing and saving of multiple signals using the sequence options in conjunction with stimuli provided via the MT2000. Signals may be displayed and saved in waveform or Data format (Hex or Binary). In the case of memory, bus or I/O defects, data can be continuously written/read to/from any location (e.g. the defective address). The user can then probe the relevant components and compare the measured signal/data with the expected signal/data.

In No-Boot Mode the microprocessor's reset line is pulsed each time the sample button is pressed. On the reset becoming inactive the microprocessor boots and the logic probe is used to capture the first 1024 data and address bits at boot up. These may be saved in sequence and displayed in hex, binary or as waveforms for analysis or auto compare with a known good unit instantly, identifying the faulty bit or control signal.

A defect Log/Analyzer is a database which contains a comprehensive record of any defects located in previous tests. Defects from the log, along with their causes can be 'posted' to a defect analyzer database, thus building an accurate statistic, which can be referred to immediately identifying the most likely component to cause the specific functional failure found on the unit under test.

HOST SYSTEMS SUPPORTED:  
IBM PC/AT or compatible

PROCESSORS SUPPORTED:  
i960 Cx, Kx, Sx, Jx and Hx Processors

AVAILABILITY:  
Now

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